

TC7MZ573FK

Low Voltage Octal D-Type Latch with 5 V Tolerant Inputs and Outputs

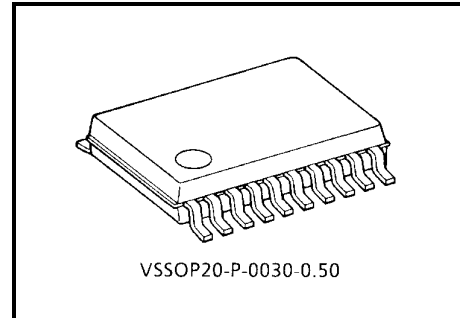
The TC7MZ573FK is a high performance CMOS octal D-type latch. Designed for use in 3.3 V systems, it achieves high speed operation while maintaining the CMOS low power dissipation.

The device is designed for low-voltage (3.3 V) V_{CC} applications, but it could be used to interface to 5 V supply environment for both inputs and outputs.

This 8 bit D-type latch is controlled by a latch enable input (LE) and an output enable input (\overline{OE}).

When the \overline{OE} input is high, the eight outputs are in a high impedance state.

All inputs are equipped with protection circuits against static discharge.

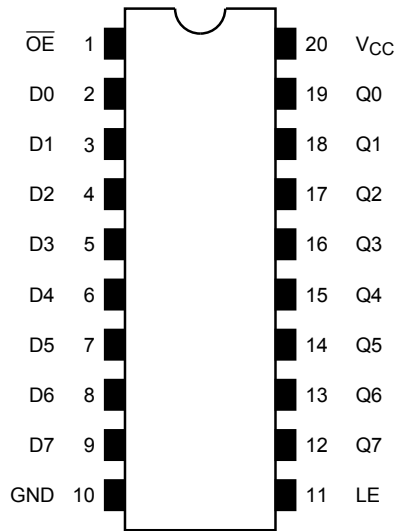


Weight: 0.03 g (typ.)

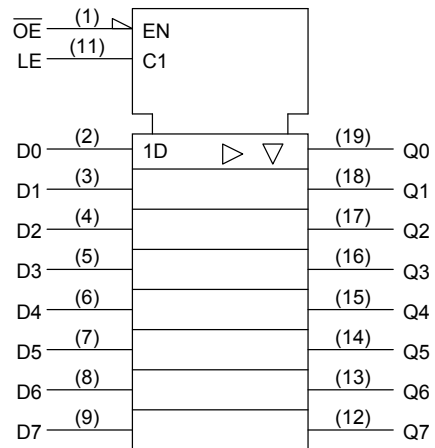
Features

- Low voltage operation: $V_{CC} = 2.0\sim 3.6$ V
- High speed operation: $t_{pd} = 8.0$ ns (max) ($V_{CC} = 3.0\sim 3.6$ V)
- Output current: $|I_{OH}|/I_{OL} = 24$ mA (min) ($V_{CC} = 3.0$ V)
- Latch-up performance: -500 mA
- Package: VSSOP (US20)
- Power down protection is provided on all inputs and outputs.
- Pin and function compatible with the 74 series (74AC/VHC/HC/F/ALS/LS etc.) 573 type.

Pin Assignment (top view)



IEC Logic Symbol



Truth Table

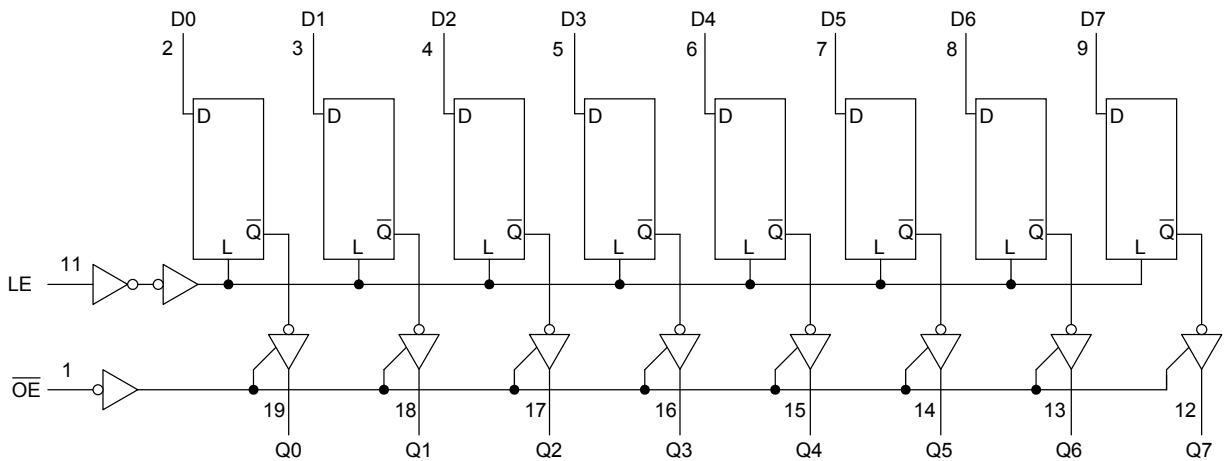
Inputs			Outputs
\overline{OE}	LE	D	
H	X	X	Z
L	L	X	Q_n
L	H	L	L
L	H	H	H

X: Don't care

Z: High impedance

Q_n : Q outputs are latched at the time when the LE input is taken to a low logic level.

System Diagram



Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V_{CC}	-0.5~7.0	V
DC input voltage	V_{IN}	-0.5~7.0	V
DC output voltage	V_{OUT}	-0.5~7.0 (Note 2)	V
		-0.5~ $V_{CC} + 0.5$ (Note 3)	
Input diode current	I_{IK}	-50	mA
Output diode current	I_{OK}	± 50 (Note 4)	mA
DC output current	I_{OUT}	± 50	mA
Power dissipation	P_D	180	mW
DC V_{CC} /ground current	I_{CC}/I_{GND}	± 100	mA
Storage temperature	T_{stg}	-65~150	$^{\circ}C$

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: Output in off-state

Note 3: High or low state. I_{OUT} absolute maximum rating must be observed.

Note 4: $V_{OUT} < GND$, $V_{OUT} > V_{CC}$

Operating Ranges (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage	V_{CC}	2.0~3.6	V
		1.5~3.6 (Note 2)	
Input voltage	V_{IN}	0~5.5	V
Output voltage	V_{OUT}	0~5.5 (Note 3)	V
		0~ V_{CC} (Note 4)	
Output current	I_{OH}/I_{OL}	± 24 (Note 5)	mA
		± 12 (Note 6)	
Operating temperature	T_{opr}	-40~85	$^{\circ}C$
Input rise and fall time	dt/dv	0~10 (Note 7)	ns/V

Note 1: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

Note 2: Data retention only

Note 3: Output in off-state

Note 4: High or low state

Note 5: $V_{CC} = 3.0\sim 3.6$ V

Note 6: $V_{CC} = 2.7\sim 3.0$ V

Note 7: $V_{IN} = 0.8\sim 2.0$ V, $V_{CC} = 3.0$ V

Electrical Characteristics

DC Characteristics (Ta = -40~85°C)

Characteristics		Symbol	Test Condition		V _{CC} (V)	Min	Max	Unit
Input voltage	High level	V _{IH}	—		2.7~3.6	2.0	—	V
	Low level	V _{IL}	—		2.7~3.6	—	0.8	
Output voltage	High level	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -100 μA	2.7~3.6	V _{CC} - 0.2	—	V
				I _{OH} = -12 mA	2.7	2.2	—	
				I _{OH} = -18 mA	3.0	2.4	—	
				I _{OH} = -24 mA	3.0	2.2	—	
	Low level	V _{OL}	V _{IN} = V _{IH} or V _{IL}	I _{OL} = 100 μA	2.7~3.6	—	0.2	
				I _{OL} = 12 mA	2.7	—	0.4	
				I _{OL} = 16 mA	3.0	—	0.4	
				I _{OL} = 24 mA	3.0	—	0.55	
Input leakage current		I _{IN}	V _{IN} = 0~5.5 V		2.7~3.6	—	±5.0	μA
3-state output off-state current		I _{OZ}	V _{IN} = V _{IH} or V _{IL} V _{OUT} = 0~5.5 V		2.7~3.6	—	±5.0	μA
Power off leakage current		I _{OFF}	V _{IN} /V _{OUT} = 5.5 V		0	—	10.0	μA
Quiescent supply current		I _{CC}	V _{IN} = V _{CC} or GND		2.7~3.6	—	10.0	μA
			V _{IN} /V _{OUT} = 3.6~5.5 V		2.7~3.6	—	±10.0	
Increase in I _{CC} per input		ΔI _{CC}	V _{IH} = V _{CC} - 0.6 V		2.7~3.6	—	500	

AC Characteristics (Ta = -40~85°C)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Min	Max	Unit
Propagation delay time (D-Q)	t _{pLH}	Figure 1, Figure 2	2.7	—	9.0	ns
	t _{pHL}		3.3 ± 0.3	1.5	8.0	
Propagation delay time (LE-Q)	t _{pLH}	Figure 1, Figure 2	2.7	—	9.5	ns
	t _{pHL}		3.3 ± 0.3	1.5	8.5	
Output enable time	t _{pZL}	Figure 1, Figure 3	2.7	—	9.5	ns
	t _{pZH}		3.3 ± 0.3	1.5	8.5	
Output disable time	t _{pLZ}	Figure 1, Figure 3	2.7	—	7.0	ns
	t _{pHZ}		3.3 ± 0.3	1.5	6.5	
Minimum pulse width (LE)	t _w (H)	Figure 1, Figure 2	2.7	3.3	—	ns
			3.3 ± 0.3	3.3	—	
Minimum set-up time	t _s	Figure 1, Figure 2	2.7	2.5	—	ns
			3.3 ± 0.3	2.5	—	
Minimum hold time	t _h	Figure 1, Figure 2	2.7	1.5	—	ns
			3.3 ± 0.3	1.5	—	
Output to output skew	t _{osLH}	(Note)	2.7	—	—	ns
	t _{osHL}		3.3 ± 0.3	—	1.0	

Note: This parameter is guaranteed by design.

$$(t_{osLH} = |t_{pLHm} - t_{pLHn}|, t_{osHL} = |t_{pHLm} - t_{pHLn}|)$$

Dynamic Switching Characteristics

(Ta = 25°C, Input: t_r = t_f = 2.5 ns, C_L = 50 pF, R_L = 500 Ω)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Typ.	Unit	
Quiet output maximum dynamic	V _{OL}	V _{OLP}	V _{IH} = 3.3 V, V _{IL} = 0 V	3.3	0.8	V
Quiet output minimum dynamic	V _{OL}	V _{OLV}	V _{IH} = 3.3 V, V _{IL} = 0 V	3.3	0.8	V

Capacitive Characteristics (Ta = 25°C)

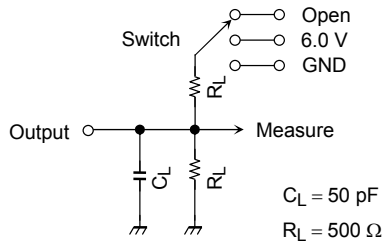
Characteristics	Symbol	Test Condition	V _{CC} (V)	Typ.	Unit	
Input capacitance	C _{IN}	—	3.3	7	pF	
Output capacitance	C _{OUT}	—	3.3	8	pF	
Power dissipation capacitance	C _{PD}	f _{IN} = 10 MHz	(Note)	3.3	25	pF

Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption.

Average operating current can be obtained by the equation:

$$I_{CC} (opr) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8 \text{ (per bit)}$$

AC Test Circuit



Parameter	Switch
t_{pLH} , t_{pHL}	Open
t_{pLZ} , t_{pZL}	6.0 V
t_{pHZ} , t_{pZH}	GND
t_w , t_s , t_h	Open

Figure 1

AC Waveform

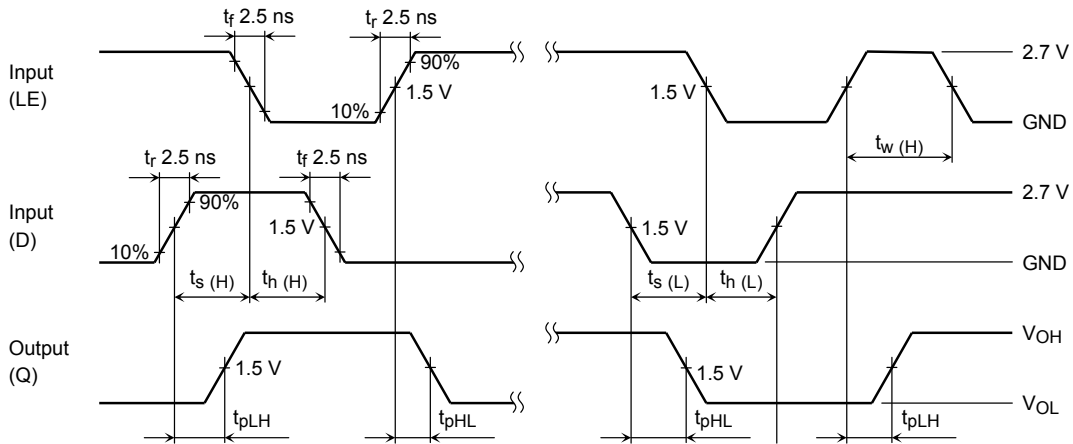


Figure 2 t_{pLH} , t_{pHL} , t_w , t_s , t_h

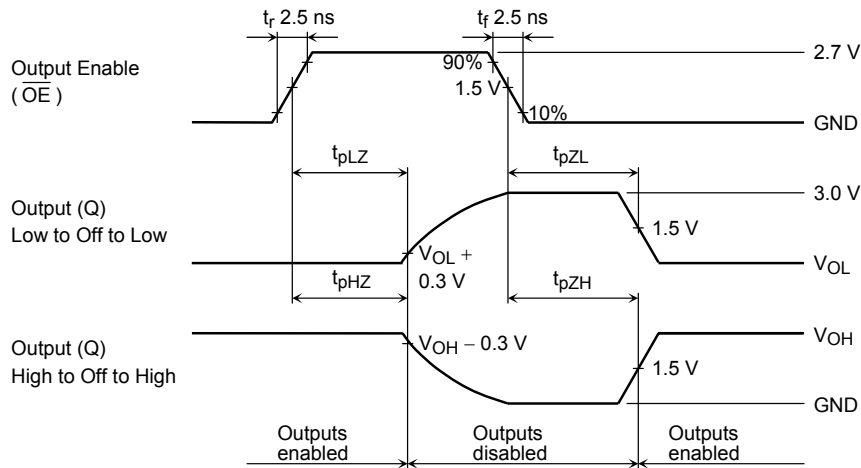
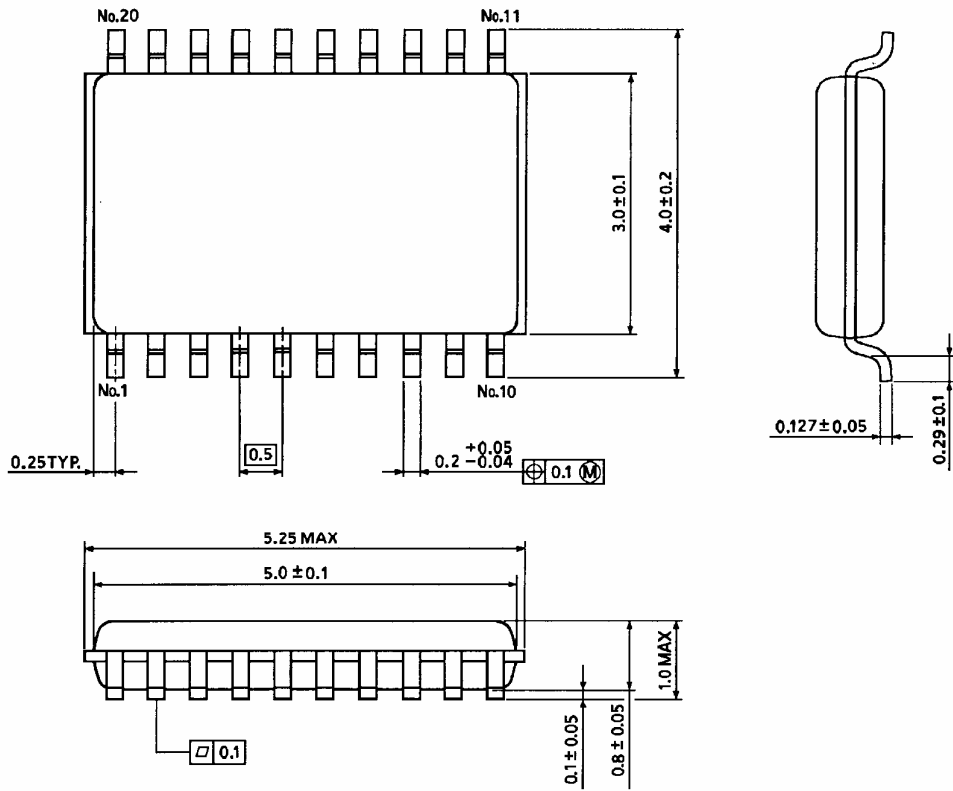


Figure 3 t_{pLZ} , t_{pHZ} , t_{pZL} , t_{pZH}

Package Dimensions

VSSOP20-P-0030-0.50

Unit : mm



Weight: 0.03 g (typ.)

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20070701-EN GENERAL

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